

(19)
(12)

(KR)
(A)

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2004 12 31

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(22) 2004 06 16

(30) 10/464,254 2003 06 17 (US)

(71) 1076 1

(72) 94062 502

95037 483

(74)

⋮

(54) 가

1

1

2 (),

3a 3f ,

3a ,

3b (liftoff) ,

3c ,

3d (leads) ,

3e ,

3f (overlay) ,

4a 4h (),

4a ,

4b (patterned photoresist) ,

4c ,

4d ,

4e (hard) ,

4f ,

4g ,

4h ,

5 ဂ

400

402 :

406 :

408 :

412 :

414a, 414b, 414c :

416a, 416b, 416c :

ဂ

2 (shield) 2
 ead gap) 가
 , 가
 (magnetic biasing field)

가 , (magnetic pole)

가 ,
 가

가

2
 가 , 2
 가

(spatial resolution)
 가

2
 가

1	가 (108)가	(100)	(104)	(102)	(102)	(102)
6)가 4	(110)	(100)	(110)	(112)	(118)	(112) 11 (102)
	가	,	,	,	,	

4g

가

	2가	가	4g	(420)	1	4g	(425)
(424)	(42)		(426)		(416b)		
	,		(410)		(416a, 416b)		
			(416b)			(424)	
(410)			(426)		(416b)		(425)
			(414b)				(424)
			(415)				2
			(416b)				
3	8 nm		(410)				
			(422)				
(438)			(414b)				
			(414b)				
			(438)				
			(400)				
			(410)				
			(414b)				
			(416b)				
			(422)				

4h	(418a, 418b)	(430, 432)	(406)				
			(434, 436)				
				(416a, 416b)			
							(
)

5 5

4

5
(maximum field)

5

가
가

60%

8nm

2nm

가 8 nm

50%

, 60%

(bias field)

가

70%

5nm

7nm

(磁極)

가

(57)

1.

1 2 ,

1 ,

2 2

2.

1 2 ,

1 ,

1 (bias magnet)

,

가 ,

, 가

3.

2 ,

4.

2 ,

가 50%

5.

2 ,

가 , 8 nm

6.

2 ,

5 nm

7.

,

,

1 ,

1 2 , , 2

2

8.

,

,

1

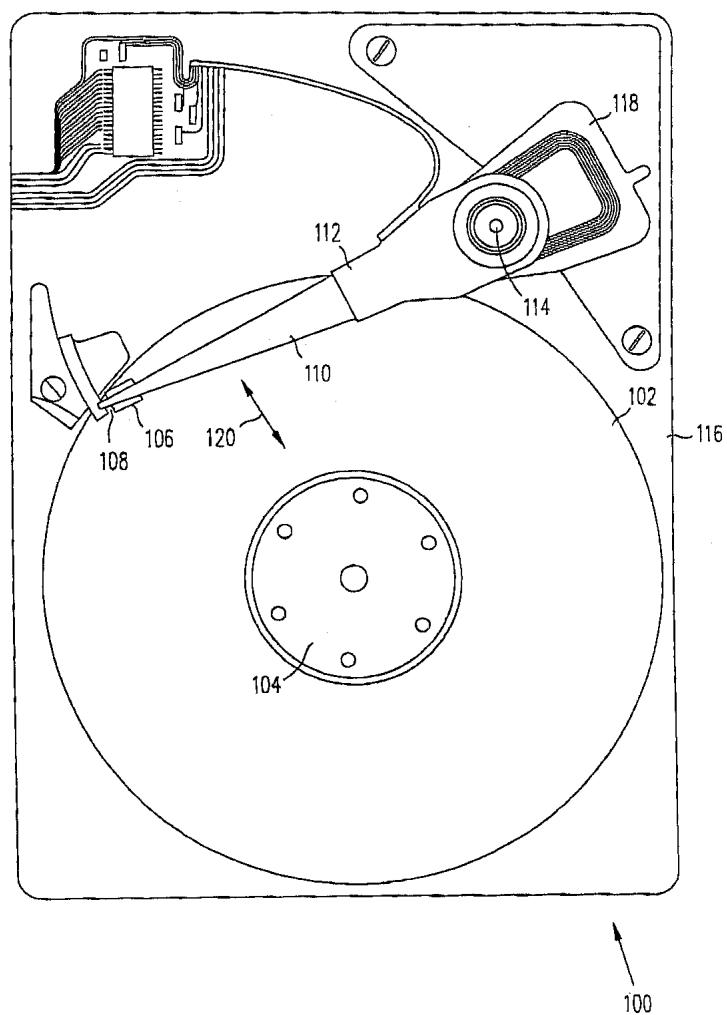
2

1

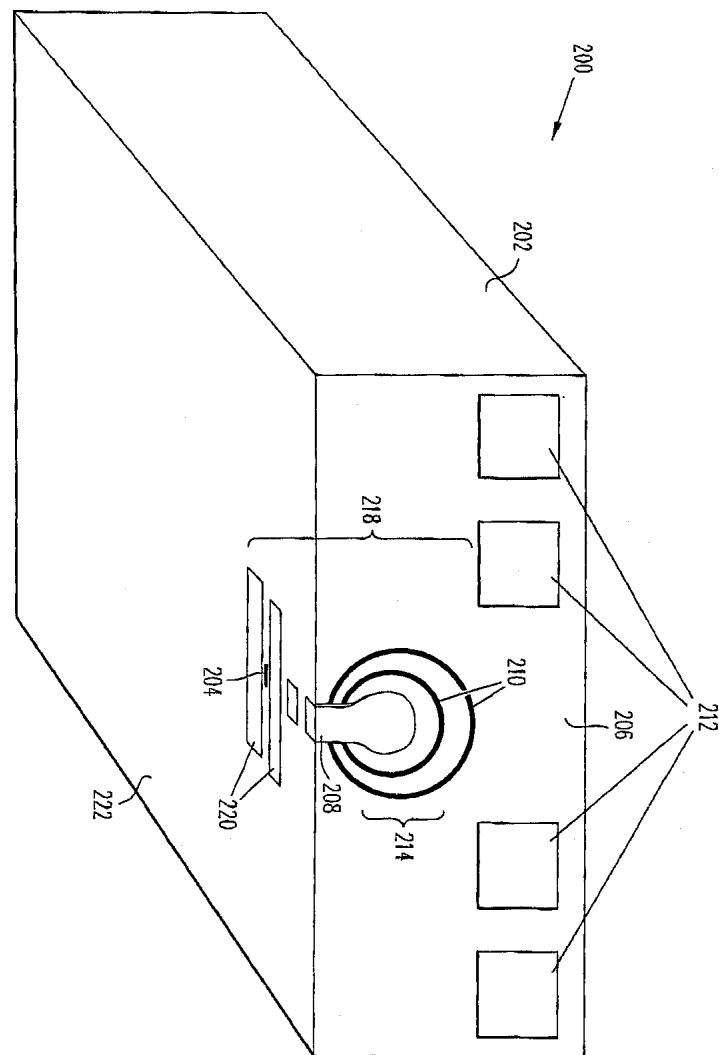
가

가

1



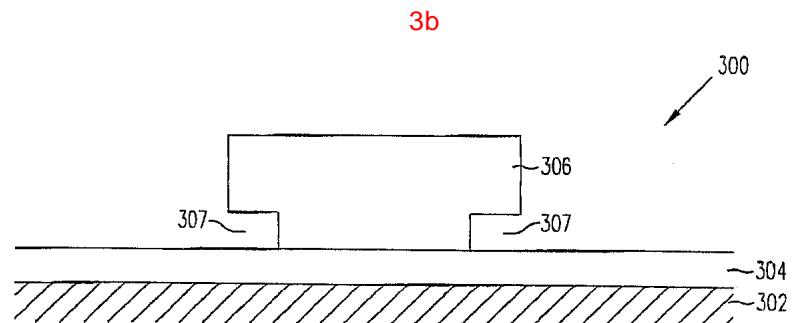
2



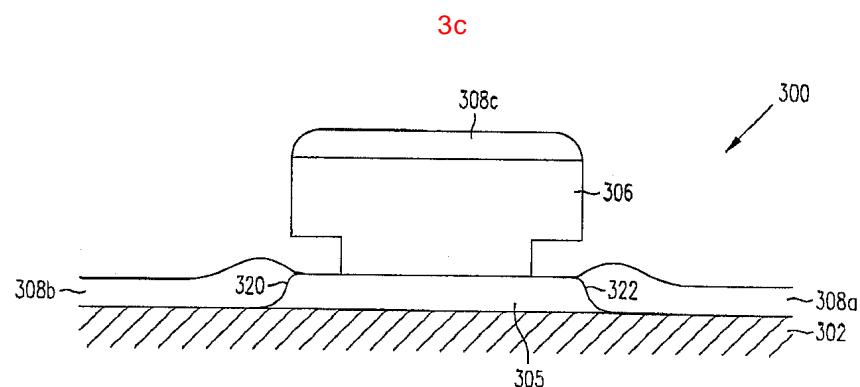
3a



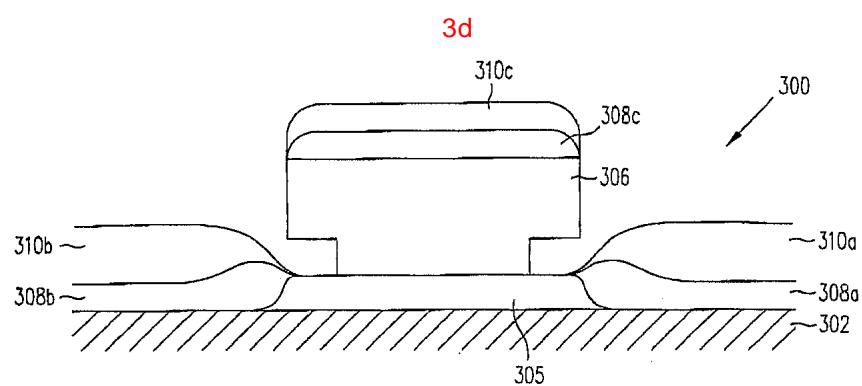
(종래 기술)



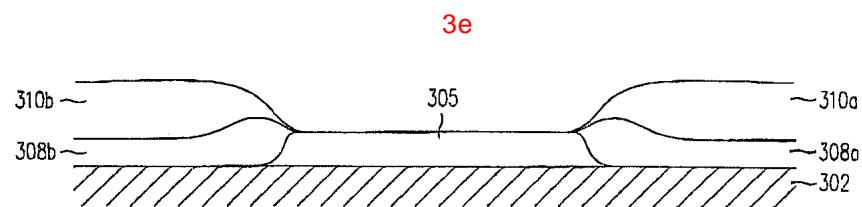
(종래 기술)



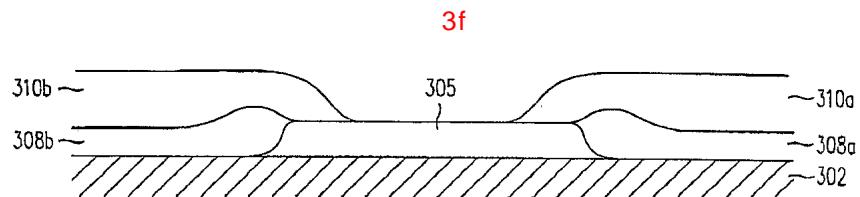
(종래 기술)



(종래 기술)

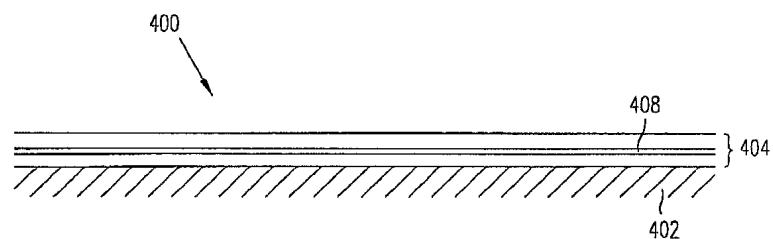


(종래 기술)

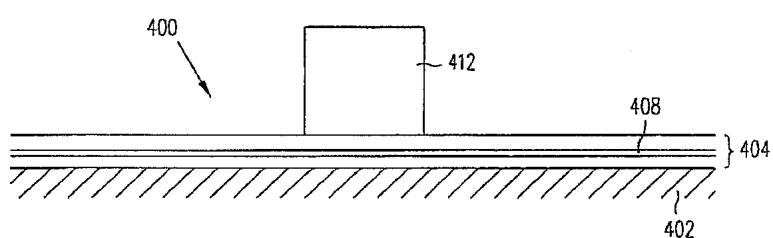


(종래 기술)

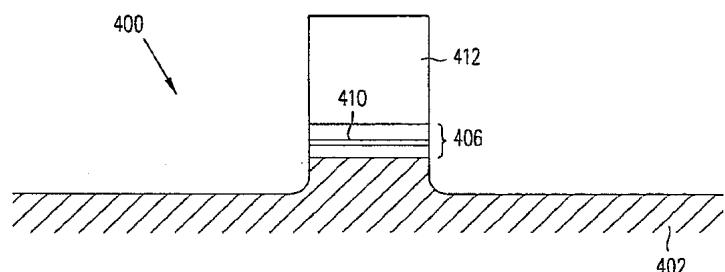
4a



4b



4c



4d

